



# Update on $Z \rightarrow e^+e^-$ analysis

Kalanand Mishra

*Fermilab*

*on behalf of Z Signal Extraction team:*

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*VBTF meeting*  
(August 27, 2010)

# Overview

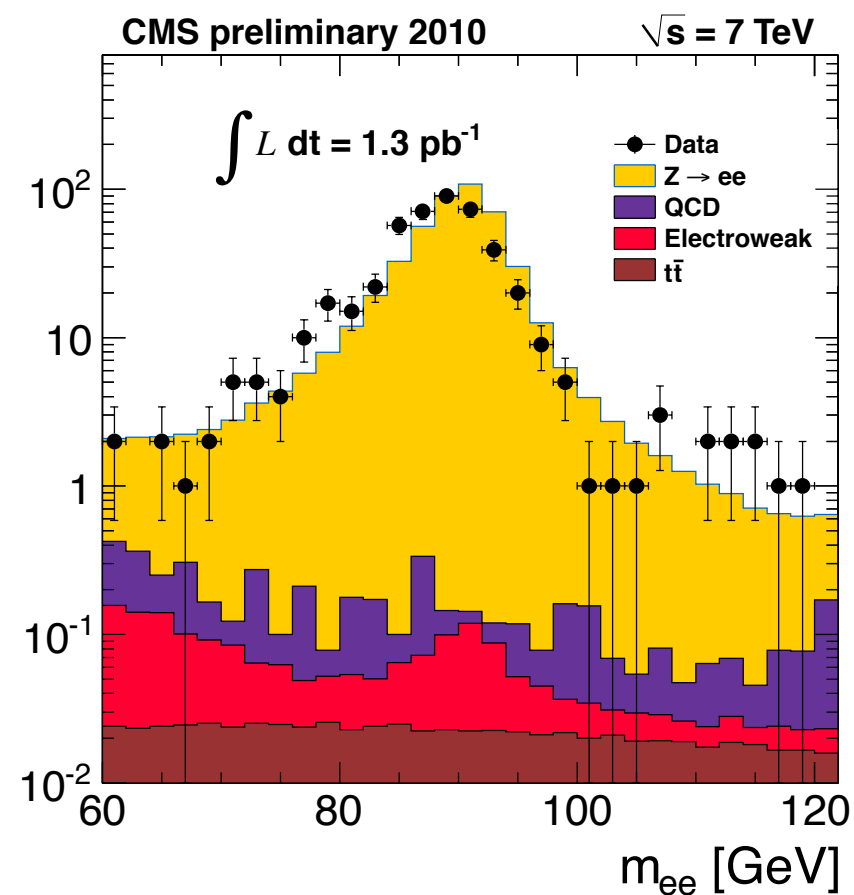
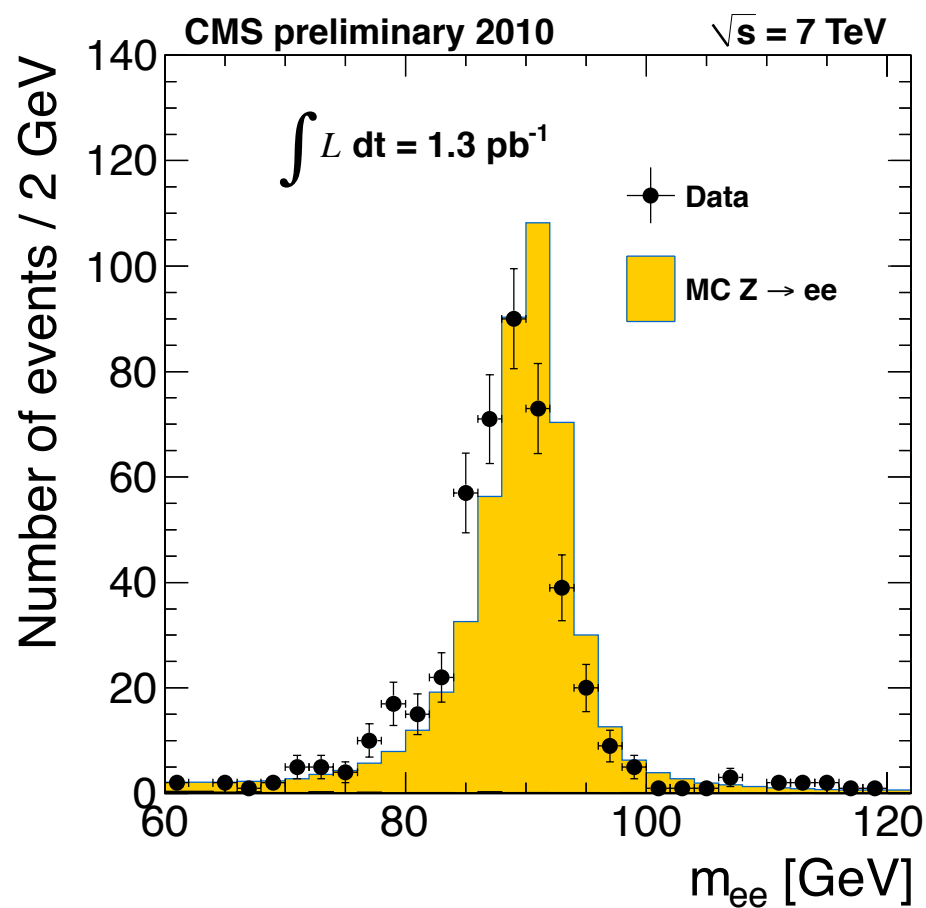


- ◆ PR plots with  $1.34 \text{ pb}^{-1}$  integrated luminosity (*i.e.*, last JSON)
- ◆ Cross section measurement update
- ◆ Status on specific topics:
  - More on simultaneous fit to estimate cross section and eff
  - Data-driven background subtraction and systematics
  - Electron efficiency systematics due to energy scale
  - Systematics in Z acceptance due to electron energy scale
  - Improvements in CMSSW\_3.8.1

# PR plots with $1.34 \text{ pb}^{-1}$ data



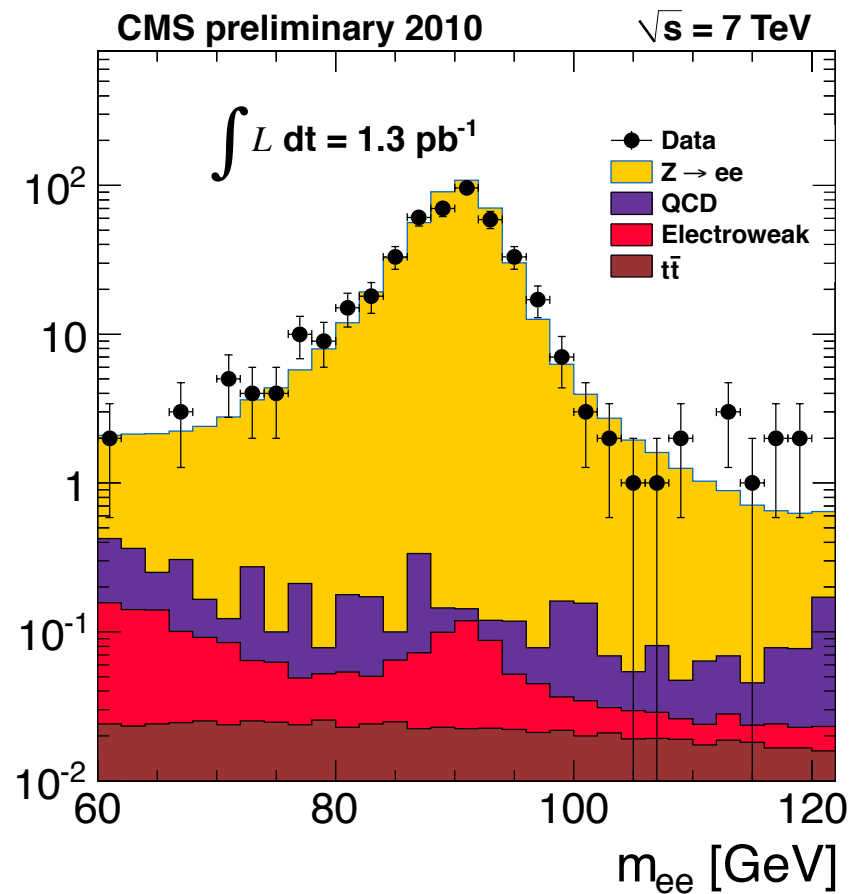
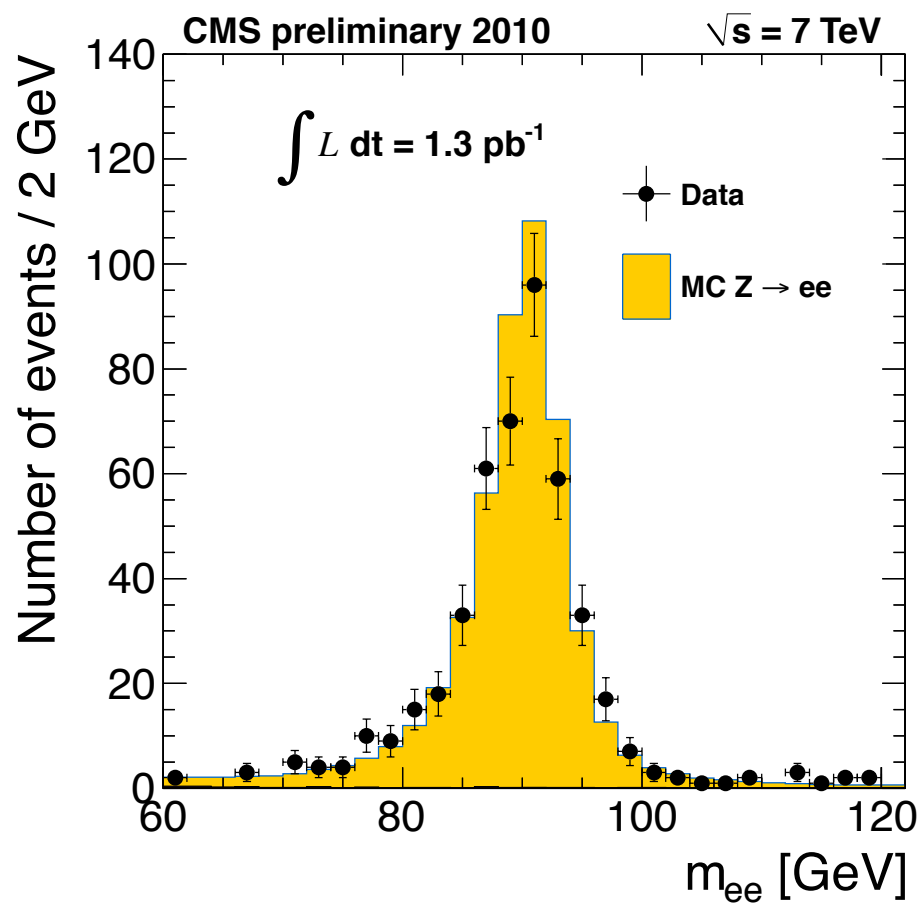
◆ Have 463 golden  $Z \rightarrow ee$  candidates.



# Z → ee mass after energy scale correction



Z mass shift = -0.8% for EBEB and -2.4% for EBEE for WP95 ele (after adc2GeV corr.)

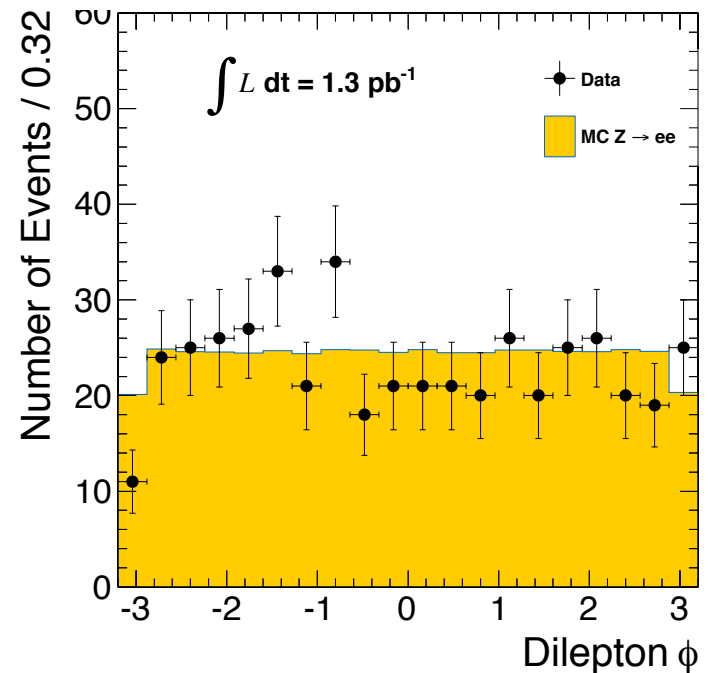
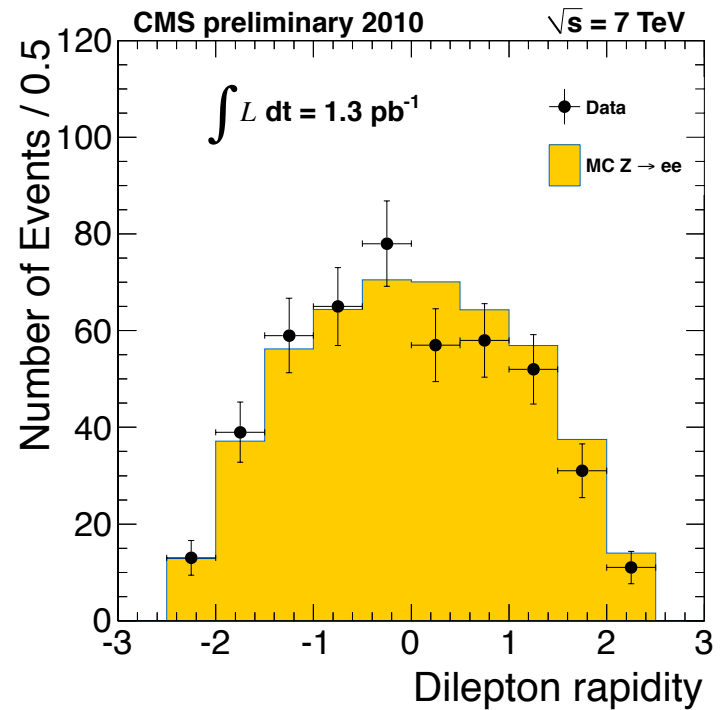
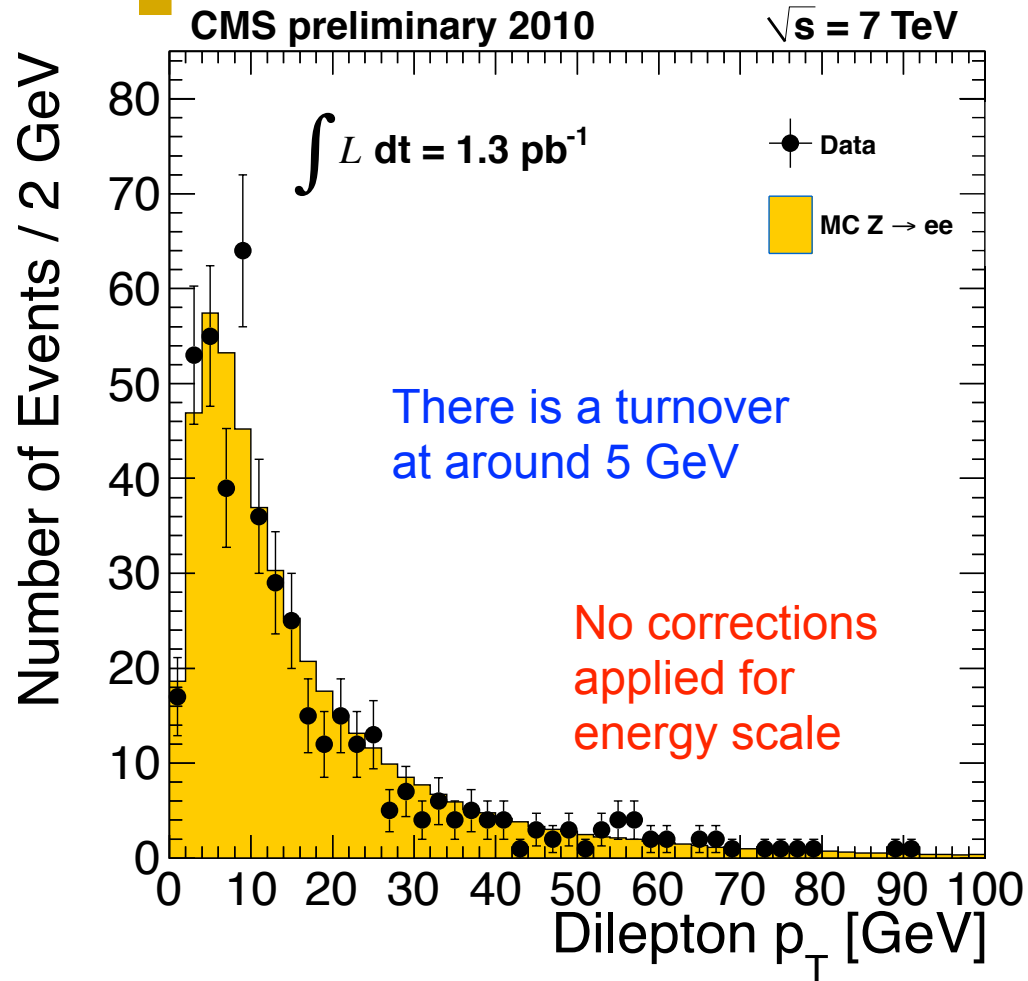


**Mass shift in  $\pi^0, \eta$ :**

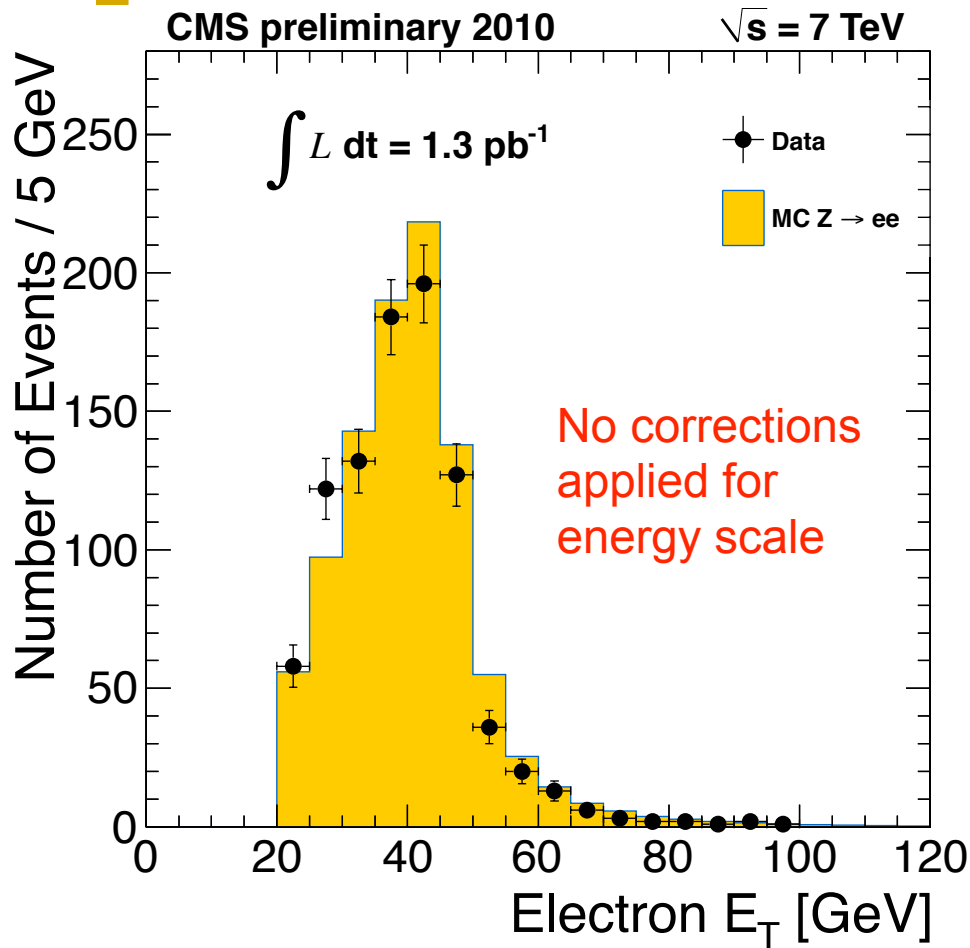
EB+EB	-0.7% ± 0.02% (stat.) ± 0.9% (syst.)
EE+EE	+2.5% ± 0.2% (stat.) ± 2.2% (syst.)

PAS: EGM-10-003

# Z p<sub>T</sub>, rapidity, azimuth

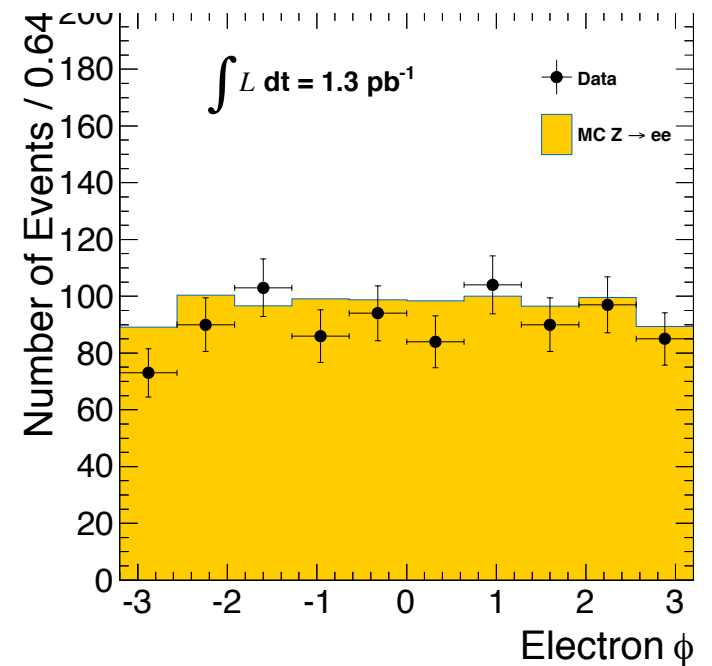
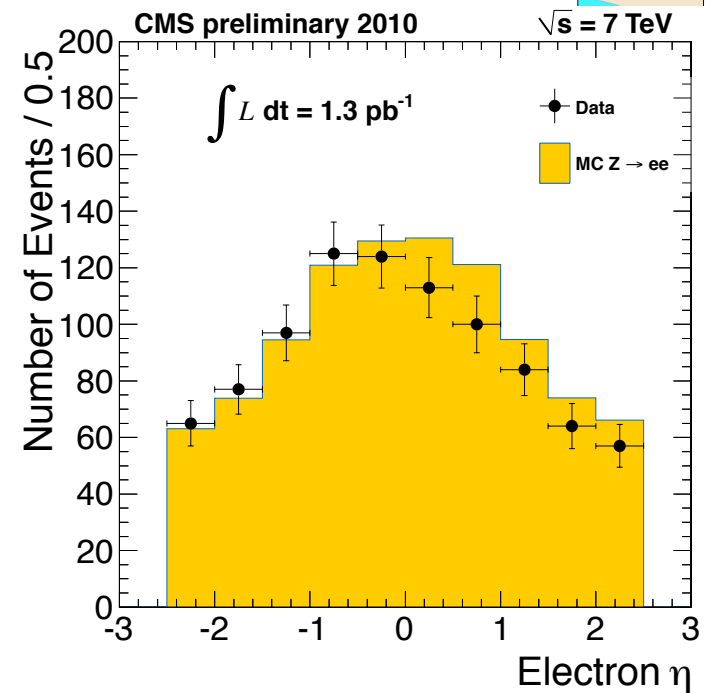


# Electron $P_T$ , rapidity, azimuth

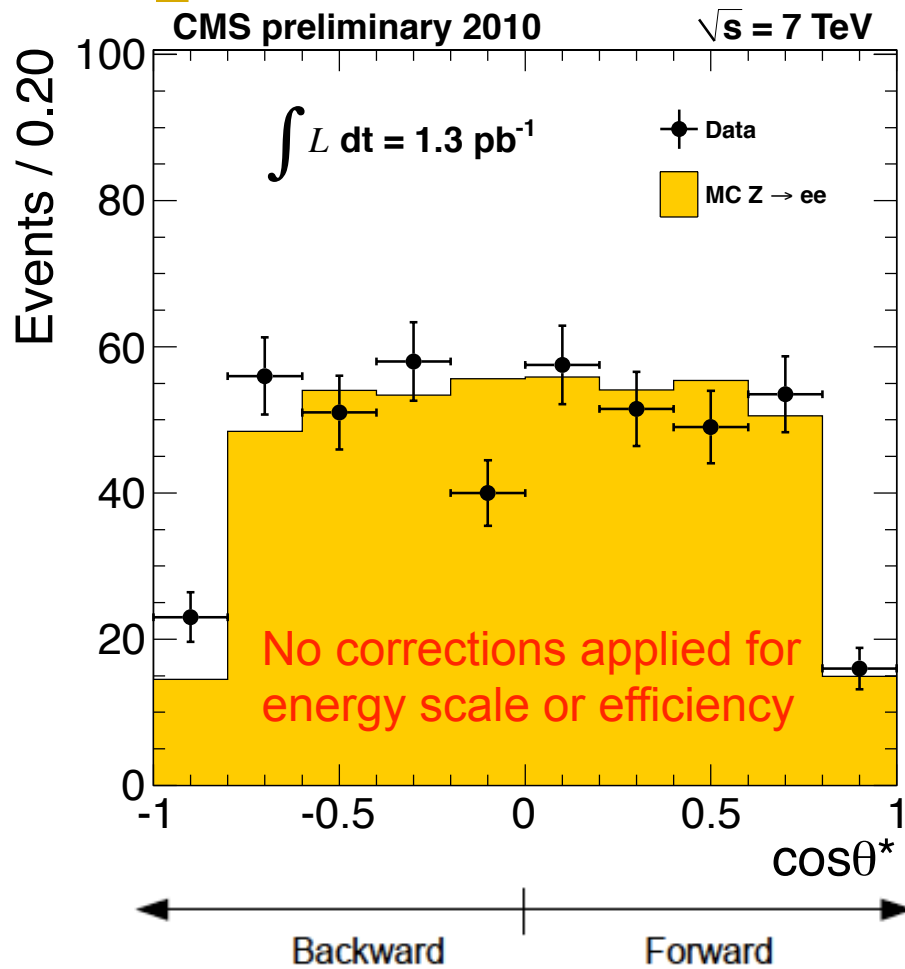


◆ Rapidity distribution is somewhat shifted to the left !

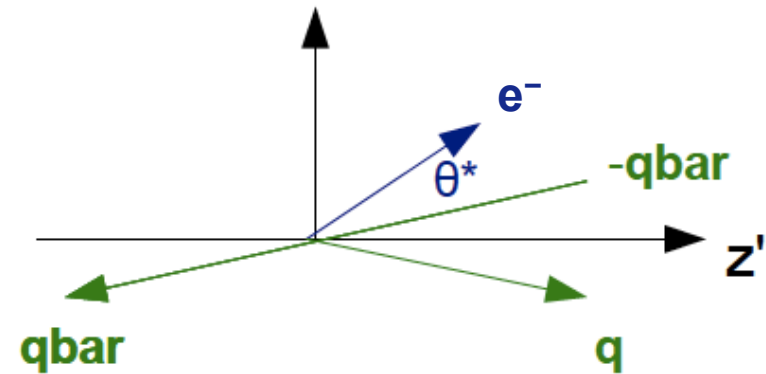
Kalanand Mishra, Ferm



# Z production topology: cosine $\theta^*$



## Collins-Soper frame

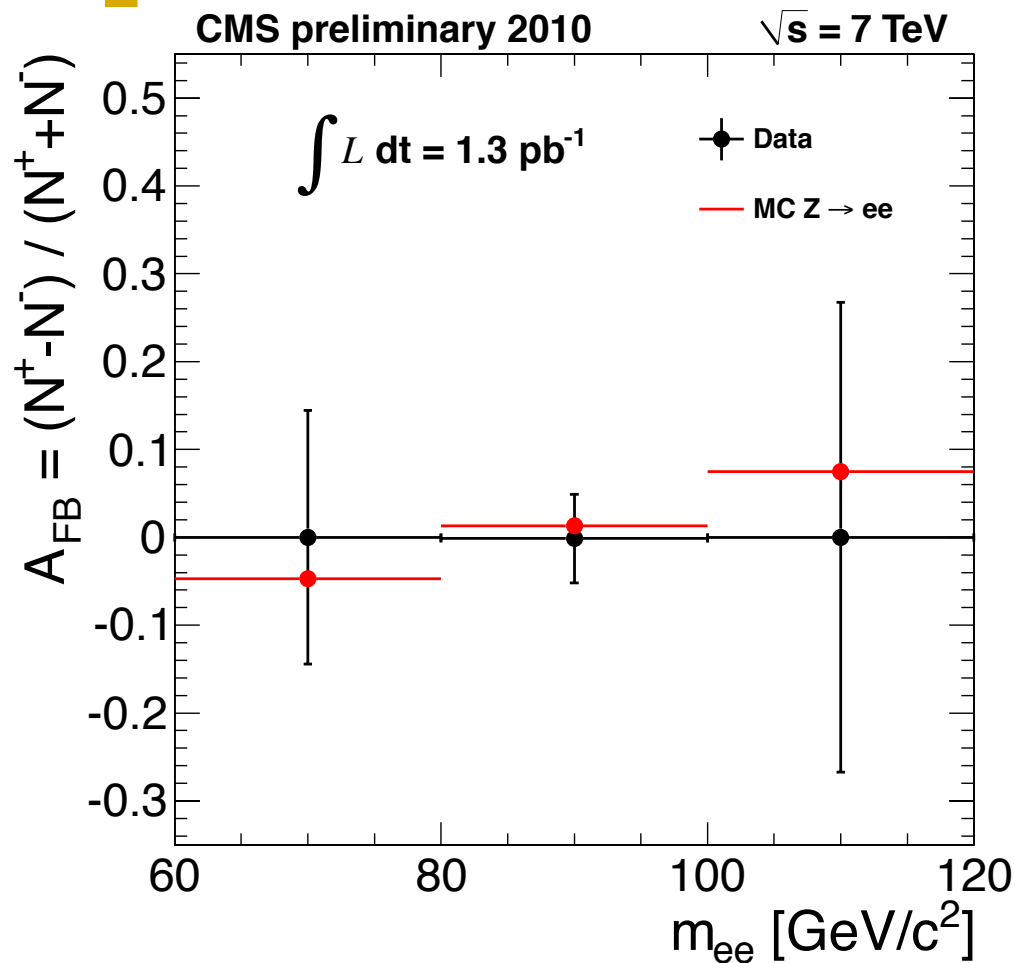


$\theta^*$  is the angle between the electron momenta and the  $z'$  axis that bisects the angle between  $\mathbf{q}$  and  $-\mathbf{qbar}$ .

*J.C. Collins and D.E. Soper, Phys. Rev. D 16, 2219 (1977)*

◆ Good agreement with NLO prediction.

# Z forward-backward asymmetry



- Forward events ( $\cos\Theta^* > 0$ )
- Backward events ( $\cos\Theta^* < 0$ )

For each Z mass bin, we compute the asymmetry given by

$$A_{fb} = \frac{(N_f - N_b)}{(N_f + N_b)}$$

Observed asymmetry is consistent with NLO predictions.

# Z → ee cross section using $\int L = 1.34 \text{ pb}^{-1}$



$N_{selected}$	$463 \pm 21.5$	
$N_{bkgd}$	$4.9 \pm 0.9$	(from MC)
$\epsilon$	$0.8671 \pm 0.0023$ (MC stat.) $\pm 0.0867$ (syst.)	dilepton efficiency
Acceptance	$0.4357 \pm 0.0010$ (MC stat.) $\pm 0.0131$ (syst.)	
Integrated Luminosity	$1.34 \pm 0.15 \text{ pb}^{-1}$ (syst.)	
$\sigma_{\gamma Z} \times BR(\gamma^* Z \rightarrow e^+e^-)$	$904.9 \pm 42.5$ (stat.) + $69.5$ (syst.) + $99.5$ (lumi.)	
Theoretical prediction	NLO prediction = $970 \pm 20 \text{ pb}$ (1607 pb for $m_Z > 20 \text{ GeV}$ )	

Acceptance = 43.6%	← from MC
Efficiency = 86.7%	
Cross section = $905 \pm 42 \text{ pb}$	← our result
NLO prediction = $970 \pm 20 \text{ pb}$	

Breakdown of syst:  $5 \oplus 5\%$  for efficiency  $\oplus 3\%$  for acceptance  $\oplus 100\%$  of bkg

Data-driven background estimation and efficiency available now. Close to MC.

# Simultaneous fit for cross section & efficiency



Parameter	Value	HiError, LoError
1 TF Bkg Expo	-0.009	+0.007, -0.007
2 e $\pm$ Efficiency	0.946	+0.018, -0.021
3 TF nBkg	73.3	+12.1, -11.3
4 TF resolution	0.87	+3.05, -4.37
5 TT resolution	2.36	+0.29, -0.29
6 Cross section	892.1	+51.7, -49.4

## Corr. matrix

NO. GLOBAL	1	2	3	4	5	6	
1	0.108	1.00	-0.10	-0.08	0.00	0.00	0.07
2	0.756	-0.10	1.00	0.63	-0.42	0.00	-0.63
3	0.644	-0.08	0.63	1.00	-0.35	0.00	-0.46
4	0.437	0.00	-0.42	-0.35	1.00	0.00	0.30
5	0.000	0.00	0.00	0.00	0.00	1.00	0.00
6	0.638	0.07	-0.63	-0.46	0.30	0.00	1.00

- ◆ Reconstructed Z line shape taken from NLO MC. Apply a resolution function
- ◆ The high purity sample assumed background-free, -we subtract the residual tiny background a posteriori.

eff = 89.5% in data Vs. 86.7 % in MC

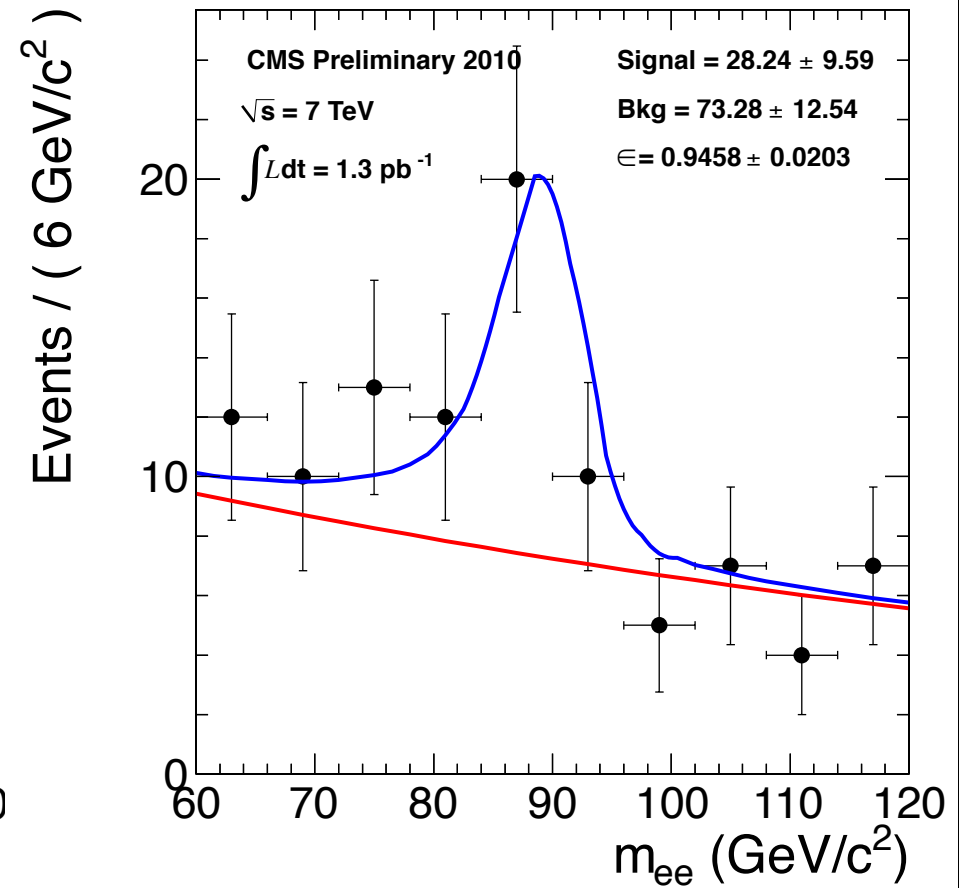
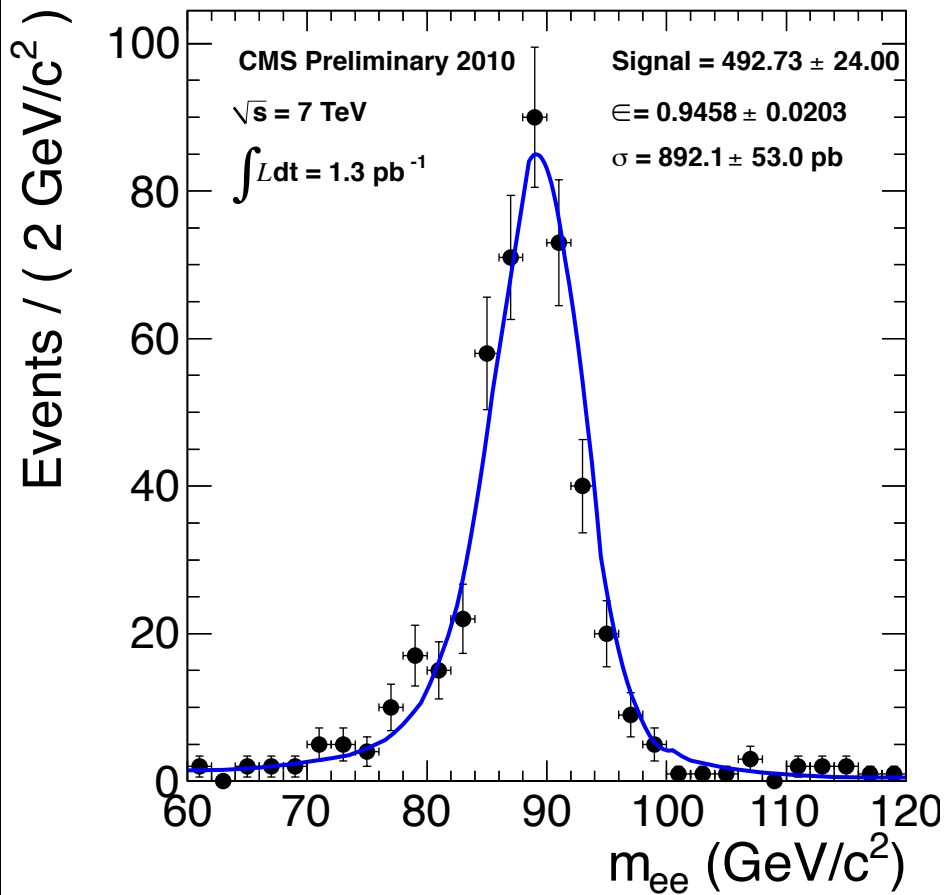
cross section after bkg subtraction  
 $\sigma = 882.7 \pm 51.7$  (stat)  $\pm 27.9$  (syst) pb

904.9  $\pm$  42.5  $\pm$  69.5 from simple counting

Small syst. uncertainty due to signal shape and e $\pm$  energy scale yet to be included. Also, working on improving some qualitative features of the fit.

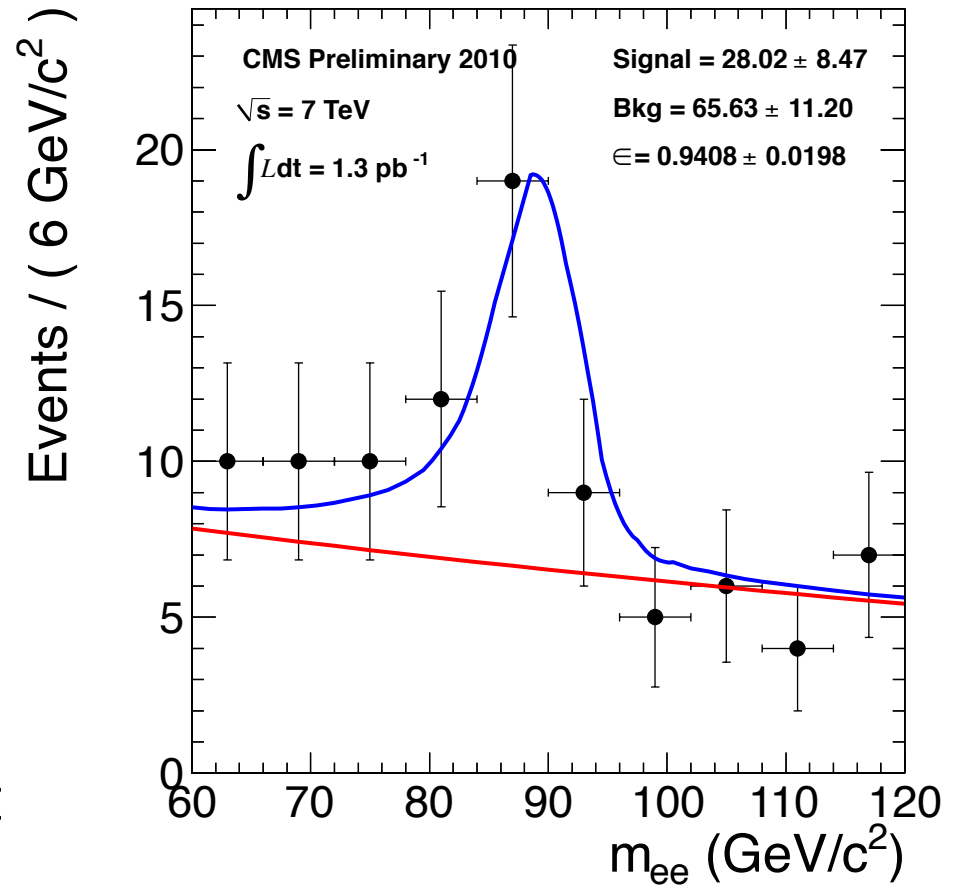
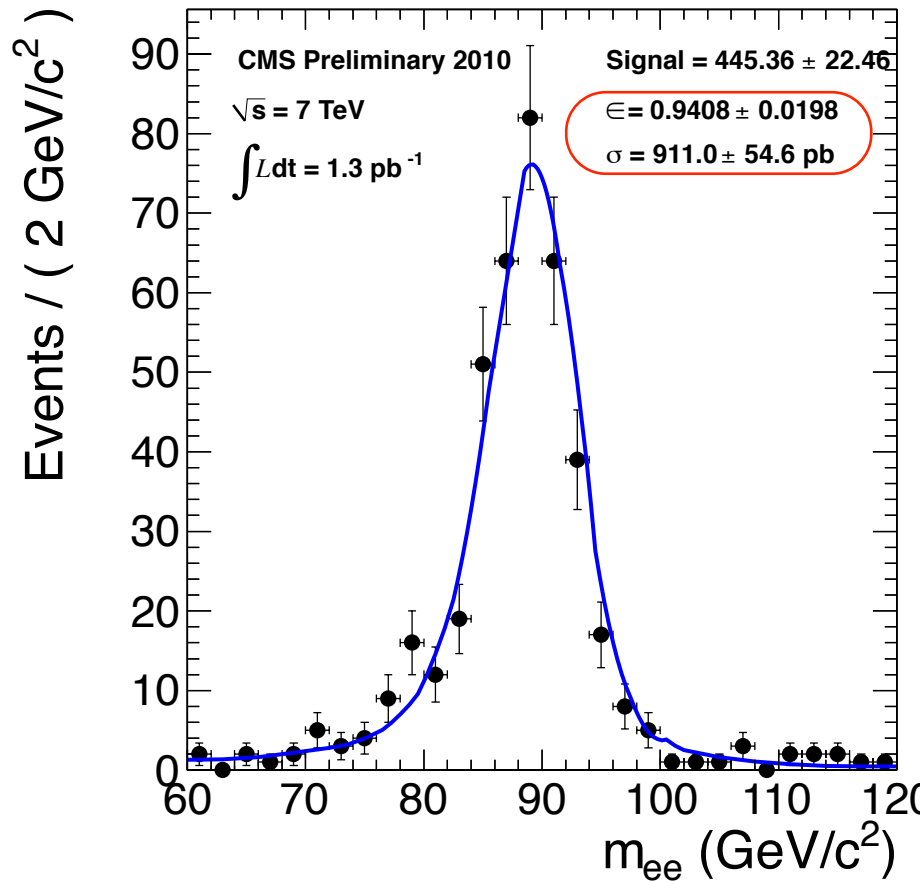
Simultaneous fit now gives more precise result on cross section than simple counting !  
The measurement is now gradually becoming systematics limited.

# Simultaneous fit plots



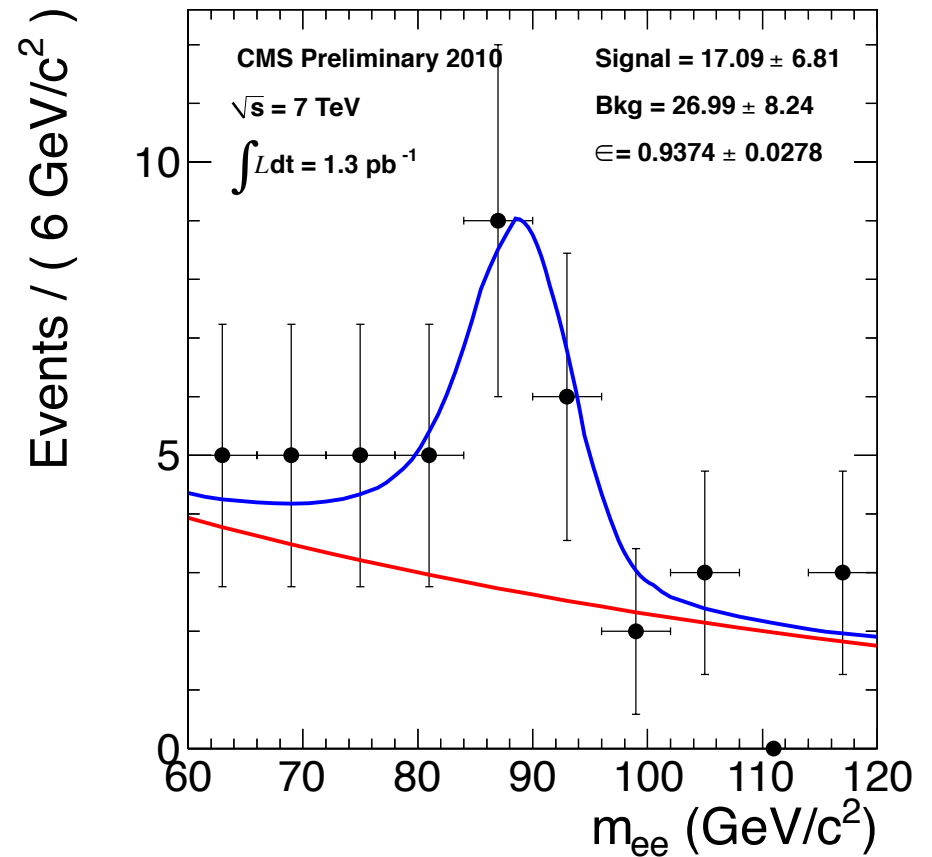
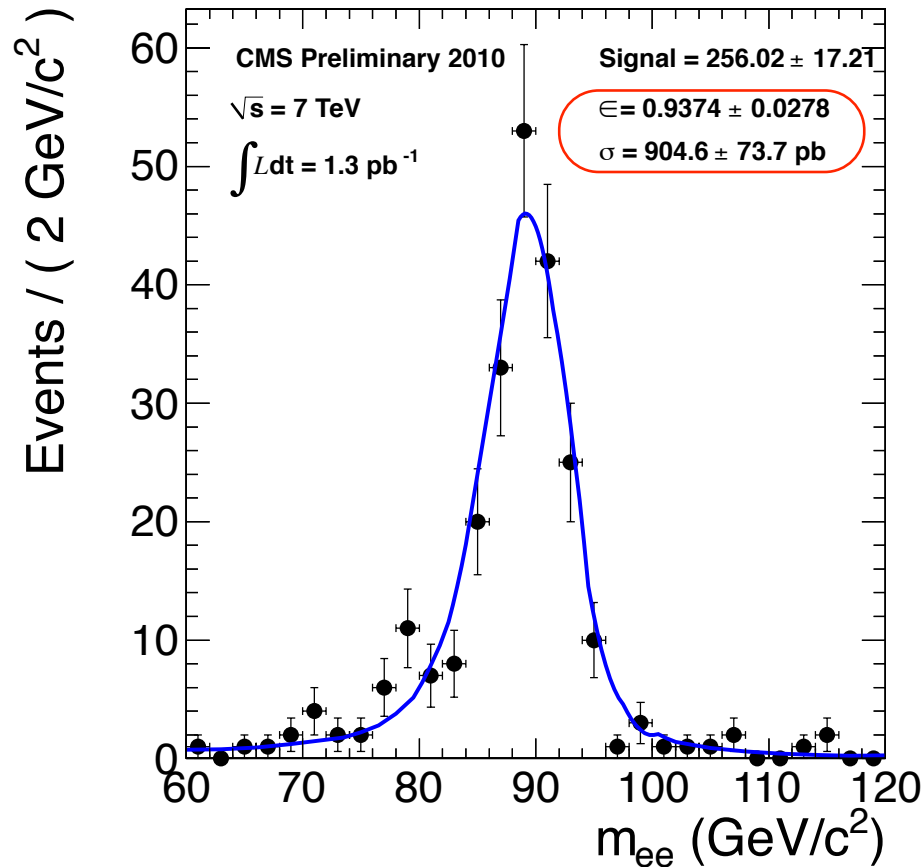
- ◆ Fit gives cross section and electron (reco⊗id) efficiency directly from data.
- ◆ Any shift in Z mass peak position gets absorbed in the resolution.

# What if we remove EE-EE combination ?



- ◆ Since EE-EE combination has smaller S/B ratio, removing it may help.
- ◆ Turns out that at this point this does not help by much.

# Barrel-only measurement



◆ Results look consistent

# Data driven electron efficiency from Z



super cluster → gsfElectron

	Eff	$\sigma_{\text{stat}}$	$N_{\text{pass}}$	$N_{\text{fail}}$	MC
Total	99.8	0.4	552	1	98.6
Barrel	100.0	1.2	398	0	99.1
Endcap	98.6	1.3	154	2	97.4

gsfElectron → WP 95

	Eff	$\sigma_{\text{stat}}$	$N_{\text{pass}}$	$N_{\text{fail}}$	MC
Total	96.2	1.0	538	21	95.2
Barrel	96.4	1.2	387	14	95.6
Endcap	95.9	1.9	152	7	94.2

WP 95 → HLT

	Eff	$\sigma_{\text{stat}}$	$N_{\text{pass}}$	$N_{\text{fail}}$	MC
Total	97.2	0.7	518	15	98.6
Barrel	99.7	0.3	386	1	99.1
Endcap	90.4	2.5	132	14	97.4

gsfElectron → WP 80

	Eff	$\sigma_{\text{stat}}$	$N_{\text{pass}}$	$N_{\text{fail}}$	MC
Total	82.4	1.9	456	97	86.3
Barrel	83.9	2.2	331	64	86.5
Endcap	79.6	3.6	127	32	85.5

- ◆ Except for WP80 efficiency, all other efficiencies are very close to MC expectation.
- ◆ Statistical uncertainty in efficiency measurement ~ 2%.

# Syst uncertainty in Eff due to energy scale



- ◆ The impact of the energy scale on electron efficiency is marginal.
- ◆ Here are the associated systematic errors we have computed:

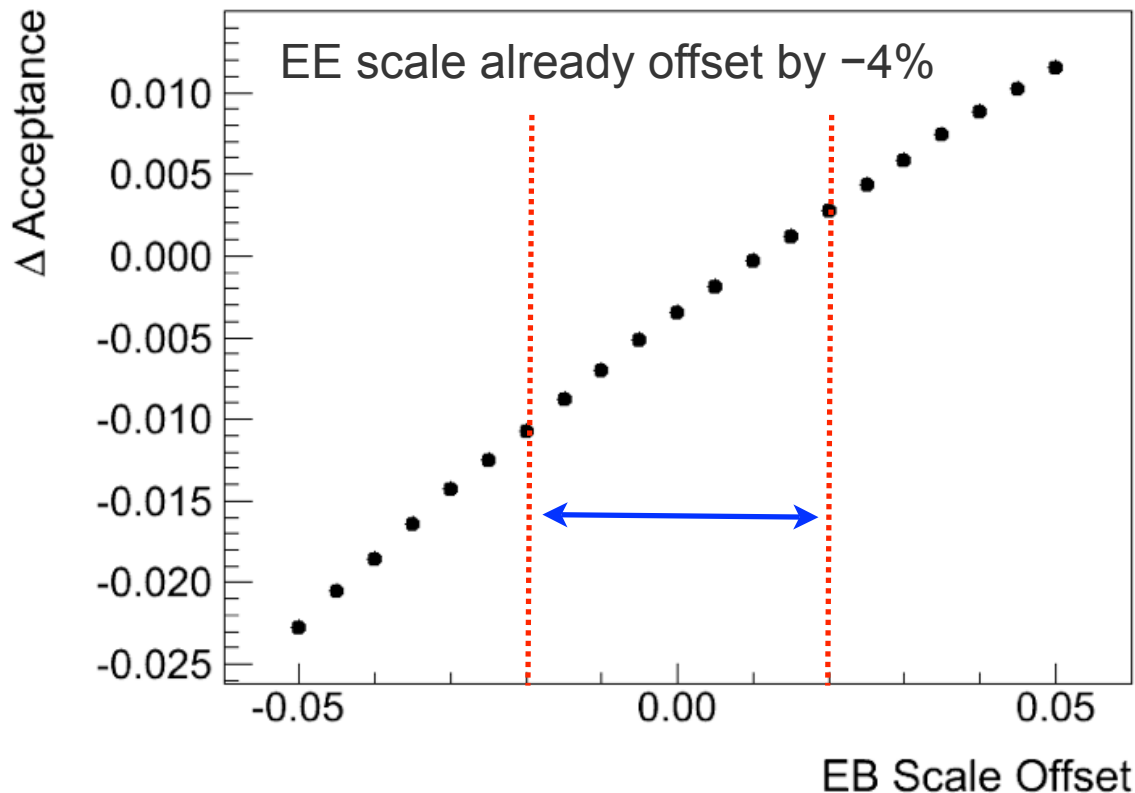
- super cluster → GsfElectron efficiency: 0.22%
- GsfElectron → WP95 efficiency: 0.10%
- GsfElectron → WP80 efficiency: 0.05%
- WP95 → HLT efficiency: 0.15%
- WP80 → HLT efficiency: 0.15%

- ◆ The methodology to estimate this systematic is simple:
  - We shifted the generator level energy scale by  $\pm 3\%$ .
  - Compute MC tag & probe efficiency (and also truth-matched efficiency) for these two samples
  - Then took the difference in the result between these 2 samples as the systematic uncertainty.
- ◆ See Jeremy Werner's talk for details.

# Syst error in Z acceptance due to energy scale



- ◆ The impact of the energy scale on Z acceptance is small.
- ◆ The plot below shows the % change in acceptance vs the change in the EB energy scale when EE energy scale has already been shifted by -4%.
- ◆ We can safely assign a maximum syst. uncertainty of 1%.

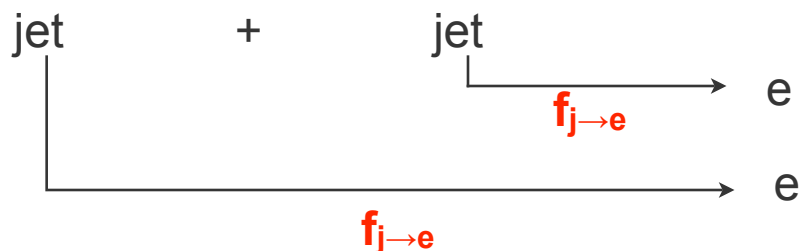


If you look at the point where EB scale is shifted -2% and EE scale is shifted -4%, you see that the acceptance changes by about 1%. So this is the maximum systematic effect we could have.



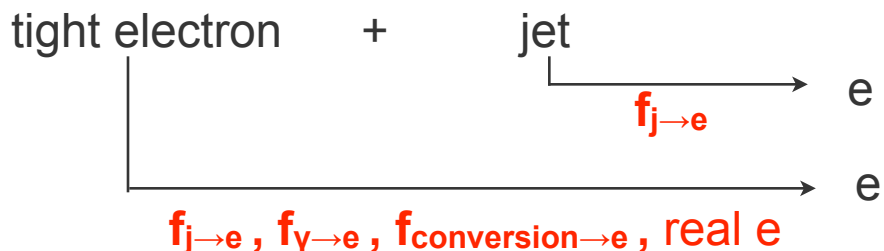
# Data-driven bkg subtraction: via fake rate

## 1. From dijet sample in data (Jet30 trigger)



fake rate from QCD dijet to ee signature =  $f_{j \to e}^2$

## 2. From electron + jet sample in data (Jet30 trigger)



fake rate from e+jet to ee =  $2 \cdot f_{j \to e}^2 \oplus f_{j \to e} \cdot f_{\gamma \to e} \oplus f_{j \to e} \cdot f_{\text{conversion} \to e} \oplus f_{j \to e}$

Note the factor of 2 ! It comes from combinatorics !

[2] - [1] gives the fake rate for  $Z \to ee$  events in data.

# Jet $\rightarrow$ electron fake rate estimation from data



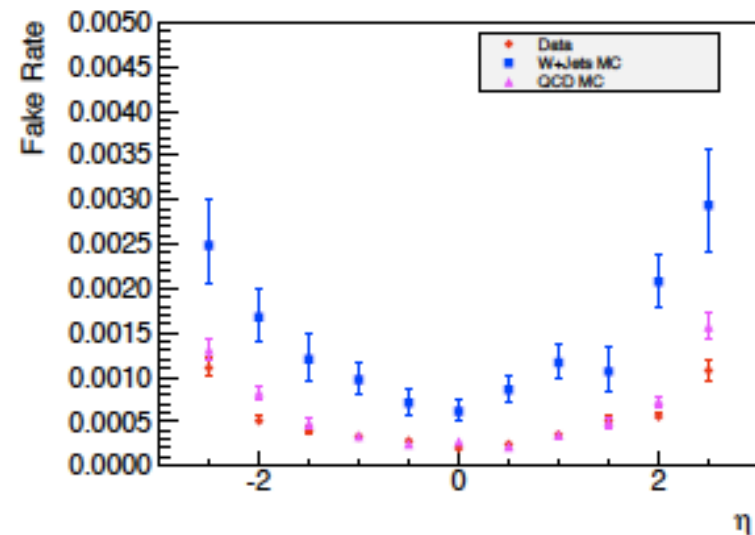
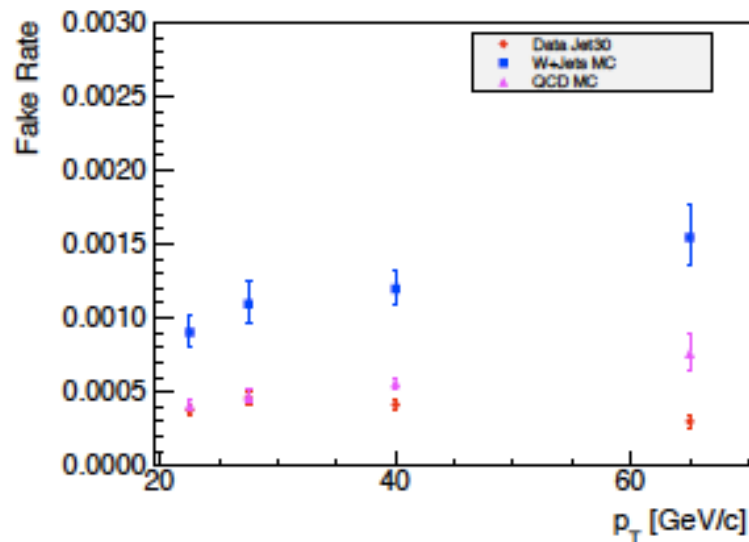
[ from Si Xie ]

jet  $\rightarrow$  WP95 fake rate

- Measurement is performed with HLT\_Jet30U trigger sample
- Measure  $\epsilon_{\text{fake}}$  as a function of  $p_T$  and  $\eta$

## • AntiKt 0.5 CaloJet $\rightarrow$ VBTF95 fake rate :

- Denominator Definition: AntiKt 0.5 CaloJet
- Numerator: VBTF 95% Working Point Electron ID+Isolation
- Veto the leading trigger jet (remove any bias due to trigger requirements)

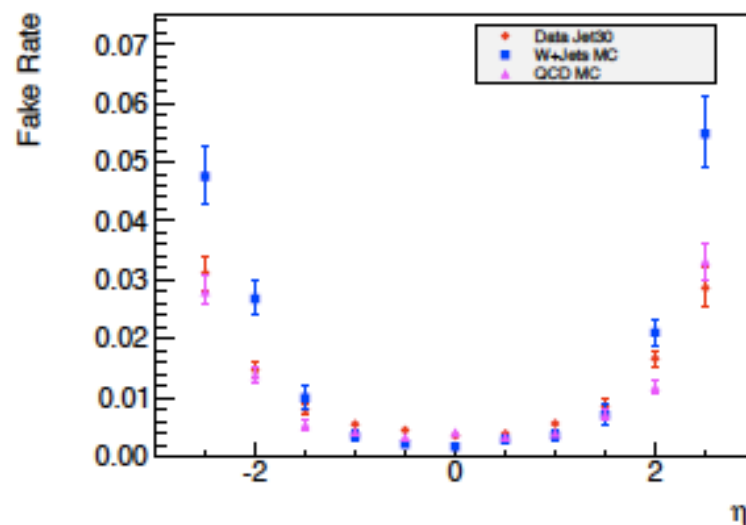
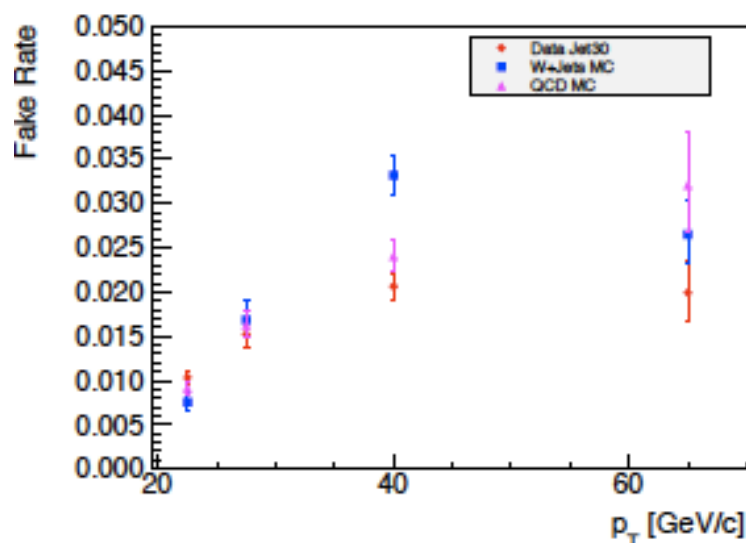




# Reco electron $\rightarrow$ WP95 fake rate

## • Reco $\rightarrow$ VBTF95 fake rate :

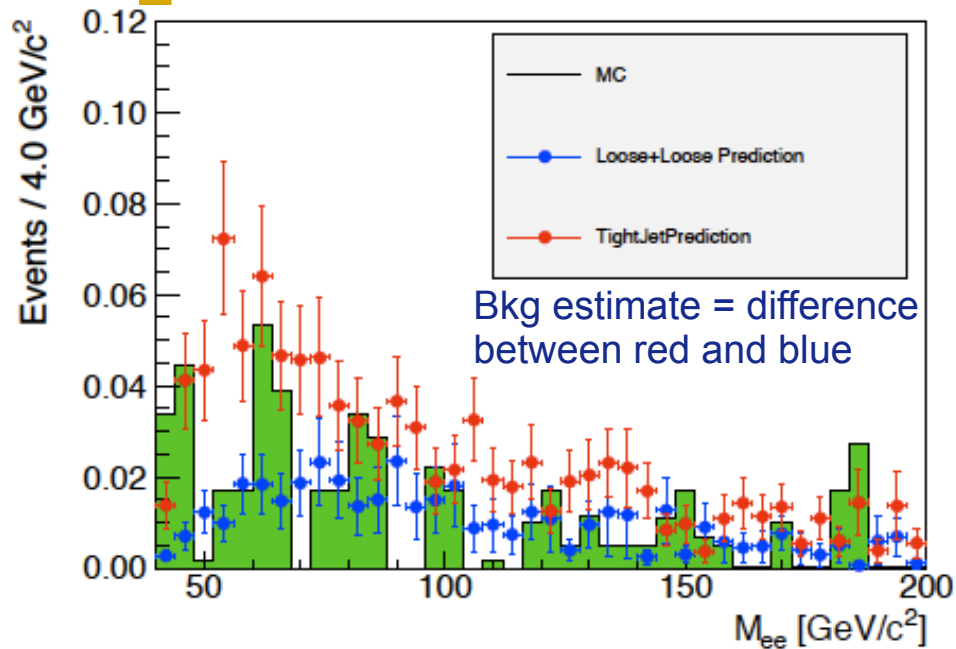
- Denominator Definition: ECAL Driven Reco Electrons
- Numerator: VBTF 95% Working Point Electron ID+Isolation
- Veto any electron candidates matching to the leading trigger jet (remove any bias due to trigger requirements)



- Agreement between QCD MC and Jet data is excellent
- W+Jets fake rate is a factor of 2-3 higher. (b/c high fraction of quark jets)

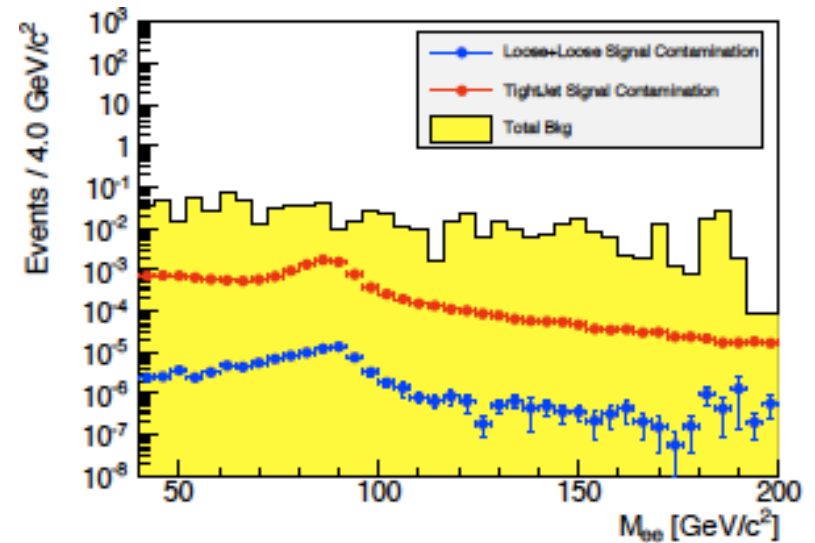
However, there are fewer W+jets &  $\gamma$ +jet background events.  
Breakdown of our background sources: 60% dijet, 20%  $\gamma$ +jet, 20% W+jet.

# Background prediction in data: $200 \text{ nb}^{-1}$



## Signal contamination

Tight e + jet:  $\sim 1\%$  signal contamination.  
Loose+Loose: Negligible signal contamin.



Tight+Jet Prediction	$0.93 \pm 0.56 \pm 0.58$ (WJets Systematics)
Loose+Loose Prediction	$0.25 \pm 0.13$
Final Prediction	$0.68 \pm 0.82$
MC Simulation Prediction	$0.42 \pm 0.07$

See Si's talk for details

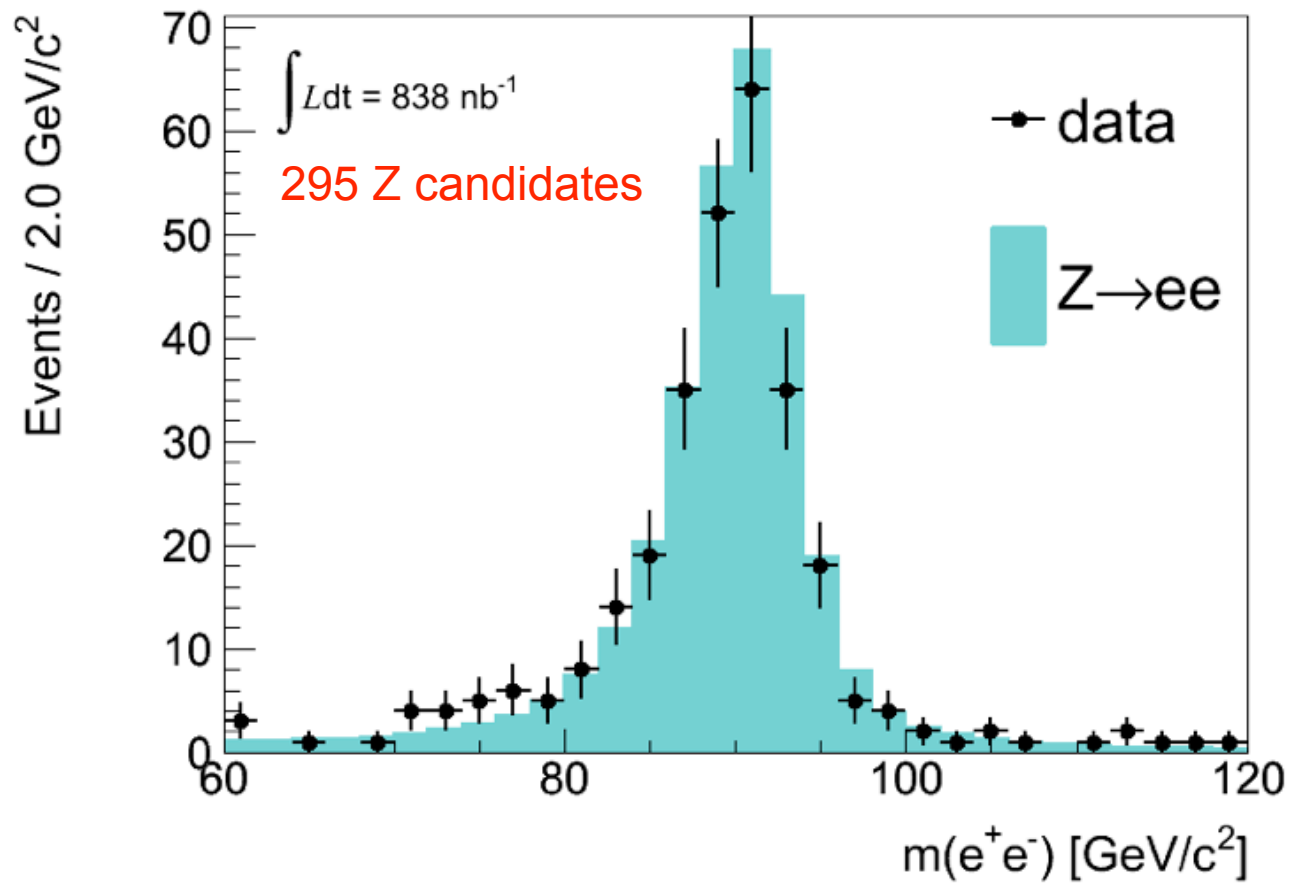
Take conservative estimates of systematic uncertainties:  
assign 100% of the difference between fake rates in data and in W+jets or  $\gamma$ +jets as syst.

# Improvements in electron calibration in 3.8.1



[ from Kevin Sung ]

We did a 3\_8\_1 private production on some of the data to get a look at improvements in the upcoming release. We note that there is a clear improvement in the Z peak position in the electron channel.



# Summary



- ◆ PR plots: All look good
- ◆ Cross section measurement
  - Both simple counting and simultaneous fit performed
  - both give consistent results
  - somewhat below NLO predictions
- ◆ Status on specific topics
  - Electron energy scale:**  $ADC2GeV$  scale come from  $\pi^0$  and  $\eta$ . Need to apply additional correction to get Z peak right.
  - Background subtraction:** Now becoming feasible for the first time. Able to estimate residual background from data-driven techniques within 200% syst. uncertainty.
  - Electron efficiency:** Efficiency in data is close to MC expectation. Syst error due to electron energy scale is marginal.
  - Z acceptance:** Syst effect due to electron energy scale is 1%.